EBL2: GAS CONDITIONS

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OUTLINE

- Gas conditions in EUV lithography
- EBL2 layout
- > Control gas environment:
 - Based on Residual Gas Analysis (RGA)
 - Based on pump speed measurements



GAS CONDITIONS IN EUV LITHOGRAPHY

- Gases in EUV lithography machines
 - > Hydrogen (purge gas, cleaning effect)
 - Contaminants (H₂O, O₂, N₂, H_xC_y)
- Research with EBL2 exposure tool focuses on studying degradation mechanisms of optics, reticles, pellicles and materials
- Well controlled gas environment is essential



BEAM LINE LAYOUT



BEAM LINE LAYOUT



Edge welded bellow P Exposure Differentially Process gas: H₂ up to 50 Pa MFC purifier chamber pumped chamber EC DPA-3 Contamination gasses: H₂O, O₂, N₂, C_xH_y, etc. H₂Otypically 1E-7 to 1E-4mbar n-tetradecane sample Differentially pumped RGA RGA \bowtie ~ chamber V1.1 orifice V1.2 80.0slm 3000slm Scope: focus on $H_2 + N_2 + O_2$

GAS ENVIRONMENT

RGA CALIBRATION IN HIGH VACUUM



RGA CALIBRATION IN ROUGH VACUUM

- > Main gas is hydrogen
- RGA is connected through an orifice
- A mixture of H₂(98.9%), N₂(1%) and O₂(0.1%) is introduced in the closed EC + DPA3 vessel, disconnected from pre pump



RGA SENSITIVITIES HYDROGEN, NITROGEN, OXYGEN

amu	1Pa	5Pa	10Pa
2	4.92E-07	5.18E-07	5.32E-07 A/mbar
14+28	1.40E-07	1.36E-07	1.38E-07 A/mbar
32	1.40E-07	5.91E-08	5.87E-08 A/mbar



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Expected detection limits:

Water: ~ 1E-5 mbar

Oxygen: ~ 3E-4 mbar

Nitrogen: ~ 2E-6 mbar

TEST: GAS MIXTURE INTRODUCED IN STEPS

- Three pressure levels (0,01; 0,03 and 0,1 mbar) set by briefly letting in the gas mix $(1\% N_2, 0.1\% O_2, balance H_2)$
- Oxygen concentration not constant and does not follow hydrogen pressure trend.
- Increasing water level suggest oxygen/hydrogen to water conversion
- Other explanation: adsorption of O_2 on walls of the exposure chamber and/or RGA chamber











PLAN B: PUMP SPEED MEASUREMENTS

Determine pump speed of individual species with and without added hydrogen

Set contaminant pressure prior to adding hydrogen, taking the pump speed change into account:

$$P_{set} = P_{required} \cdot \frac{S(with \ hydrogen)}{S(without \ hydrogen)}$$



DETERMINE PUMP SPEED AT HIGH VACUUM

- Mass flow controllers not suited (minimal flow too high): automatic leak valves need to be used
- Leak valves need to be calibrated to determine the flow rate. This is done by introducing the flow into the closed vessel.
- > The volume V of the vessel is determined using a mass flow controller: 308 ± 4 liter





PUMP SPEED AT HIGH VACUUM - NITROGEN

- $Q = V \cdot \frac{\Delta P}{\Delta t}$
- > V = 308 I
- > $\frac{\Delta P}{\Delta t}$ = 3.63E-6 mbar/s
- Q = 1.12E-3 mbarl/s
- With pumps running at the same flow:
- > P = 1.95E-6mbar

S = Q/P = 574 I/s





PUMP SPEED AT HIGH VACUUM - OXYGEN

- $Q = V \cdot \frac{\Delta P}{\Delta t}$
- > V = 308 I
- $\frac{\Delta P}{\Delta t} = 3.76\text{E-6 mbar/s}$
- Q = 1.16E-3 mbarl/s
- With pumps running at the same flow:
- P = 2.01E-6mbar

S = Q/P = 576 I/s





PUMP SPEED AT HIGH VACUUM - HYDROGEN

- $Q = V \cdot \frac{\Delta P}{\Delta t}$
- > V = 308 I
- $\frac{\Delta P}{\Delta t} = 1.475\text{E-5 mbar/s}$
- Q = 4.54E-3 mbarl/s
- > With pumps running at the same flow:
- > P = 4.93E-6mbar

S = Q/P = 922 I/s





PUMP SPEED AT ROUGH VACUUM - METHOD



PUMP SPEED AT ROUGH VACUUM - RESULTS

Measurements N_2 give best results (hatched area). Partial pressure setpoint uncertainty for N_2 appr. 12% (target 10% for all contaminant gases)

More data for O₂ and H₂O needed

For now assume $S(contaminants) = S(N_2)$





CONCLUSIONS AND RECOMMENDATIONS

- Optimize dynamic range of the RGA → increase relative pump speed for H₂, install multiple orifices, bake-out, closed ion source
- > Use dedicated gas mixtures + mass flow controllers
- CFD modelling to verify proper mixing of gases





Bronkhorst

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